

## Notice of References Cited

Application/Control No.	Applicant(s)/Patent Under Reexamination AGARWAL ET AL.		
Examiner	Art Unit		
Yennhu B. Huynh	2813	Page 1 of 1	

## U.S. PATENT DOCUMENTS

	O.S. PATENT BOSOMENTO				
*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-2002/0064915A1	05-2002	Kitamura	438/255
	В	US-2001/0023110A1	09-2001	Fukuzumi et al.	438/396
	С	US-			
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-			
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р				,	
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U				
	v				
	w				
	х				

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.